

## Notice of References Cited

Applicant(s)/Patent Under Reexamination 09/940,589 Art Unit

INOUE ET AL.

Examiner 2621 Dennis Rosario-Vasquez

Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,456,324 B1	09-2002	Yamada et al.	348/219.1
	В	US-6,217,143 B1	04-2001	Munakata et al.	347/16
	С	US-6,295,140 B1	09-2001	Kameyama, Kenji	358/461
	D	US-6,075,623 A	06-2000	Yun, Young-Jung	358/486
	Ε	US-5,371,613 A	12-1994	Arimoto et al.	358/461
	F	US-5,062,144 A	10-1991	Murakami, Shigeo	382/274
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 01233874 A	09-1989	Japan	KANEKO, YUTAKA	H04N 01/04
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	٧	
	V	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.